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Hasegawa

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 	Hits	Search String	Databases
[]	26	((logic and gate and delay adj time) and rise and fall) and logical ad	adj time) and rise and fall) and logical adj operation) an USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
7	2	(((logic and gate and delay adj time) and rise and fall) and logical ac	adj time) and rise and fall) and logical adj operation) an USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
F3	60	(((logic and gate and delay adj time) and rise and fall) and logical ac	adj time) and rise and fall) and logical adj operation) an USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L4	46970		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L5	926	hasegawa.in. and delay	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
F6	121	(hasegawa.in. and delay) and NEC	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L7	45	(hasegawa.in. and delay) and NEC	USPAT
L	12	((hasegawa.in. and delay) and NEC) and rise and fall	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
7	1628	delay adj calculat\$	US-PGPUB;
L 3	26127	look adj3 table	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L4	74	(delay adj calculat\$) and (look adj3 table)	BM
L5	က	((delay adj calculat\$) and (look adj3 table)) and library	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
Fe	473	(delay adj calculat\$) and gate	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
۲۷	29	((delay adj calculat\$) and gate) and fall and rise	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
F8	38	(((delay adj calculat\$) and gate) and fall and rise) and simulat\$	
F3	53		EPO; JPO; DERWENT;
	7	optimizing adj signal adj timing	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	106402	logic adj circuit\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	310	(logic adj circuit\$1) and (calculat\$3 adj delay)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	37	((logic adj circuit\$1) and (calculat\$3 adj delay)) and (logic\$2 adj (information or ope USPAT; US-PGPUB; EPO; JPO; DERWENT;	
	112	(logic adj circuit\$1) and (comput\$5 adj delay)	EPO; JPO; DERWENT;
	96	(logic adj circuit\$1) and (estimat\$3 adj delay)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	468	((logic adj circuit\$1) and (calculat\$3 adj delay)) or ((logic adj circuit\$1) and (comput USPAT;	US-PGPUB; EPO; JPO; DERWENT;
	26	(((logic adj circuit\$1) and (calculat\$3 adj delay)) or ((logic adj circuit\$1) and (compu USPAT; US-PGPUB; EPO; JPO; DERWENT;	US-PGPUB; EPO; JPO; DERWENT;
	7	(((logic adj circuit\$1) and (calculat\$3 adj delay)) and (logic\$2 adj (information or op USPAT; US-PGPUB; EPO; JPO; DERWENT;	ormation or op USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	2	(((logic adj circuit\$1) and (calculat\$3 adj delay)) or ((logic adj circuit\$1) and (comp USPAT; US-PGPUB;	 and (comp USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	7	(((logic adj circuit\$1) and (calculat\$3 adj delay)) or ((logic adj circuit\$1) and (comp USPAT; US-PGPUB; EPO; JPO; DERWENT;	 and (comp USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	33722	logic adj gate\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	179	(logic adj gate\$1) and (calculat\$3 adj delay)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	47	(logic adj gate\$1) and (comput\$5 adj delay)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	61	(logic adj gate\$1) and (estimat\$3 adj delay)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	268	((logic adj gate\$1) and (calculat\$3 adj delay)) or ((logic adj gate\$1)	((logic adj gate\$1) and (calculat\$3 adj delay)) or ((logic adj gate\$1) and (comput\$5 USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	38	(((logic adj gate\$1) and (calculat\$3 adj delay)) or ((logic adj gate\$1)	Iculat\$3 adj delay)) or ((logic adj gate\$1) and (comput\$t USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	0	(((logic adj gate\$1) and (calculat\$3 adj delay)) or ((logic adj gate\$1	(((logic adj gate\$1) and (calculat\$3 adj delay)) or ((logic adj gate\$1) and (comput\$ USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	220	(logic adj circuit\$1) and (delay with library)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	46	((logic adj circuit\$1) and (delay with library)) and ("connection inform	elay with library)) and ("connection information" or "circu USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB

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Semiconductor integrated circuit compensating variations of delay time Semiconductor integrated circuit device capable of producing output the Methods for designing standard cell transistor structures Automated processor generation system for designing a configurable p Semiconductor integrated circuit device capable of producing output the Semiconductor integrated circuit device and microcomputer Semiconductor integrated circuit device and microcomputer Semiconductor integrated circuit Method for designing layout of semiconductor integrated circuit. Variable delay circuit and semiconductor integrated circuit, semiconductor integrated circuit and semiconductor integrated	Source rocessor and method for the same areof without being influenced by oth and method for the same areof without being influenced by oth	2002082 326/31 2002082 326/31 20020814 327/158 20020124 327/277 20011122 326/112 20010823 326/104 20021105 716/17 20021105 716/1 20021105 326/82 20020514 327/158 20020514 327/158 20020430 327/175 20011009 716/10
Semiconductor device for setting delay time. Semiconductor device for setting delay time. Variable delay circuit and semiconductor integrated circuit device. Semiconductor integrated circuit device and microcomputer. Probe points and markers for critical paths and integrated circuit, semiconduct Method for designing layout of semiconductor integrated circuit, semiconduct Method for designing layout of semiconductor integrated circuit semiconduct Method for improving the operation of a circuit through iterative substitutions. Processor utilizing a low voltage data circuit and a high voltage controller. Logic gate size optimization process for an integrated circuit whereby circuit & Logic simulator. Delay testing of high-performance digital components by a slow-speed tester Circuit and method for detecting if a sum of two multidigit numbers equals a t	emiconductor integrated circuit obtained b miconductor integrated circuit obtained by bstitutions and performance analyses of c ntroller eby circuit speed is improved while circuit beed tester equals a third multidigit number prior to a	20010323 370303 20010410 327/279 20010130 327/278 20000801 716/4 19991109 716/6 19990713 716/7 19970826 326/80 19970408 716/6 19970225 714/37 19970225 714/732

19960416 708/525	19950829 714/814	19950620 716/6	19931214 708/525	19920623 257/204	19910319 342/45	19900515 705/75	19890214 380/283	19751021 377/2
Circuit and method for detecting if a sum of two multibit numbers equals a third multibit constant number pric 19960416 708/525	Apparatus for performing logic simulation	iming performance of a circuit	Method of detecting arithmetic or logical computation result			for continuously acknowledged link encrypting	Method and apparatus for continuously acknowledged link encrypting	IIMING CONTROL CIRCUIT FOR ELECTRONIC FUEL INJECTION SYSTEM
Circuit and r	Apparatus for	Apparatus a	Method of d	Bipolar integ	Mode 4 reply decoder	Method and	Method and	TIMING CO
US 5508950 A	US 5446748 A	US 5426591 A	US 5270955 A	US 5124776 A	US 5001751 A	US 4926478 A	US 4805216 A	US 3914580 A